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AC 2004/0142831 07/22/2004 N. Jager Lezer N. Ja					· · · · · · · · · · · · · · · · · · ·								
AD 2006/057085 03/16/2006 N. Jager Lezer								· · · · · · · · · · · · · · · · · · ·					
AE 3,802,841 04/09/1974 Jean-Baptisto Robin													
AF S,324,506 06/28/1994 L. Calvo, et al.								<u> </u>					
AG 6,491,931 12/10/2002 N. Collin				04/09/1974	Jean-Baptiste Robin			· · · · · · · · · · · · · · · · · · ·					
AH 6,503,521 01/07/2003 B. Alis, et al.				06/28/1994	<u> </u>								
AI 6,955,805 10/18/2005 A. Shah, et al.				12/10/2002	N. Collin								
AJ				01/07/2003	B. Atis, et al.								
AK		Al	6,955,805	10/18/2005	A. Shah, et al.								
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AQ EP 1 208 836 05/29/2002 EPO		AO	EP 1 201 221	05/02/2002	EPO (Corresponds to US 2002/098217)		1	Х					
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AR EP 0 445 342 09/11/1991 EPO			DD 4.000.00	0.5 /5.5 /5.5									
AS WO 00/72809 12/07/2000 WIPO X AT JP H09-263 518 10/07/1997 Japan (English Abstract Provided) X AU JP 2002-154932 05/28/2002 Japan (English Abstract Provided) X OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.) AW AX AY AZ Date Considered *Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in			L	1									
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	AO	JP 2001-48750	1	Japan (English Abstract Provided)			X					
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	_	JP 2000-344627		Japan (English Abstract Provided)			X					
		JP 2002-173412	L	Japan (Corresponds to US 6,503,521)			X					
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